				Docket Number (Optional) 16592-2	Application Number 10/774,839			
INFORMATION DISCLOSURE CITATION OUse several sheets if necessary)				Applicant(s) Gary S. Tompa, et al.				
(NIE 21 70% E				Filing Date Group Art Unit 2878				
U.S. PATENT DOCUMENTS								
INITIAL	EXAMER DATE INITIAL PRADE DOCUMENT NUMBER DATE 2002/0174367 11/21/02		NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE		
CH		2002/0174367	11/21/02	Kimmel et al.	713	201		Ì
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CH		JP 10132944	5/22/98	Jeon-Seo Park	G01T1	17		+
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CH		Brent R. Blaes and Martin G. Buehler, "SEU/SRAM as a Process Monitor", IEEE Transactions on Semiconductor Manufacturing, Vol. 7, No. 3, August, 1994, Pages 319-324						
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Examiner Signature CONSTANTINE HANNAHER Date Considered JAN 4 2006 EXAMINER: Initial it citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through								
citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								
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